# **Power MOSFET**

# -20 V, -4.1 A, Dual P-Channel ChipFET™

#### **Features**

- Offers an Ultra Low R<sub>DS(ON)</sub> Solution in the ChipFET Package
- Miniature ChipFET Package 40% Smaller Footprint than TSOP-6
- Low Profile (<1.1 mm) Allows it to Fit Easily into Extremely Thin Environments such as Portable Electronics
- Simplifies Circuit Design since Additional Boost Circuits for Gate Voltages are not Required
- Operated at Standard Logic Level Gate Drive, Facilitating Future Migration to Lower Levels using the same Basic Topology
- Pb-Free Package is Available

#### **Applications**

- Optimized for Battery and Load Management Applications in Portable Equipment such as MP3 Players, Cell Phones, and PDAs
- Charge Control in Battery Chargers
- Buck and Boost Converters

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit	
Drain-to-Source Voltage			$V_{DSS}$	-20	V	
Gate-to-Source Voltage			$V_{GS}$	±8.0	V	
Continuous Drain	Stoody Stoto	T <sub>A</sub> = 25°C	I <sub>D</sub>	-2.9	Α	
Current (Note 1)	Steady State	T <sub>A</sub> = 85°C		-2.1		
	t ≤ 10 s	T <sub>A</sub> = 25°C		-4.1		
Power Dissipation (Note 1)	Steady State	T 25°C	$P_{D}$	1.1	W	
	t ≤ 10 s	$T_A = 25^{\circ}C$		2.1		
Pulsed Drain Current	tp = 10 ms		I <sub>DM</sub>	-13.8	Α	
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	–55 to 150	°C	
Source Current (Body Diode)			IS	-1.1	Α	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C	

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Ambient, Steady State (Note 1)	0	113	°C/W
Junction-to-Ambient, t ≤ 10s (Note 1)	$R_{\theta JA}$	60	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

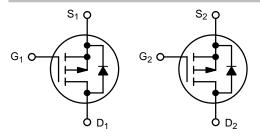
 Surface mounted on FR4 board using 1 in sq pad size (Cu area = 1.127 in sq [1 oz] including traces)



### ON Semiconductor®

#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> TYP	I <sub>D</sub> MAX
–20 V	64 mΩ @ -4.5 V	
	85 mΩ @ -2.5 V	-4.1 A
	120 mΩ @ –1.8 V	

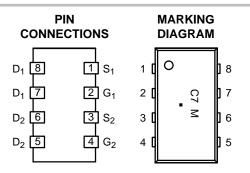


P-Channel MOSFET

P-Channel MOSFET



ChipFET CASE 1206A STYLE 2



C7 = Specific Device Code

M = Month Code

■ = Pb-Free Package

#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTHD4102PT1	ChipFET	3000/Tape & Reel
NTHD4102PT1G	ChipFET (Pb-Free)	3000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Characteristic	Symbol	Test Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•	•	u.			•
Drain-to-Source Breakdown Voltage	V <sub>(Br)DSS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(Br)DSS/</sub> T <sub>J</sub>			-15		mV/°C
Zero Gate Voltage Drain Current	ate Voltage Drain Current $I_{DSS}$ $V_{CS} = 0 \text{ V}$ $T_{J} = 25^{\circ}\text{C}$		;		-1.0	μΑ
		$V_{GS} = 0 V$ $V_{DS} = -16 V$ $T_{J} = 85^{\circ}C$	;		-5.0	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8.0 \text{ V}$			±100	nA
ON CHARACTERISTICS (Note 2)						
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.45		-1.5	V
Gate Threshold Temperature Coefficient	$V_{GS(TH)/}T_J$			2.7		mV/°C
Drain-to-Source On Resistance	R <sub>DS(ON)</sub>	$V_{GS} = -4.5 \text{ V}, I_D = -2.9 \text{ A}$		64	80	mΩ
		$V_{GS} = -2.5 \text{ V}, I_D = -2.2 \text{ A}$		85	110	
		$V_{DS} = -1.8 \text{ V}, I_D = -1.0 \text{ A}$		120	170	
Forward Transconductance	9FS	$V_{DS} = -10 \text{ V}, I_D = -2.9 \text{ A}$		7.0		S
CHARGES, CAPACITANCES, AND GATE RESIS	STANCE		•		•	
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1.0 MHz,		750		pF
Output Capacitance	C <sub>OSS</sub>	$V_{DS} = -16 \text{ V}$		100		
Reverse Transfer Capacitance	C <sub>RSS</sub>			45		
Total Gate Charge	Q <sub>G(TOT)</sub>			7.6	8.6	nC
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = -4.5 \text{ V}, V_{DS} = -16 \text{ V}$ $I_D = -2.6 \text{ A}$	',	1.3		
Gate-to-Drain Charge	$Q_{GD}$			2.6		
SWITCHING CHARACTERISTICS (Note 3)	•		•		•	
Turn-On Delay Time	t <sub>d(ON)</sub>			5.5	10	ns
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = -4.5 V, V <sub>DD</sub> = -16 \	<sub>/,</sub>	12	25	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = -2.6 \text{ A}, R_G = 2.0 \Omega$		32	40	
Fall Time	t <sub>f</sub>			23	35	
DRAIN-SOURCE DIODE CHARACTERISTICS	,	•	ı			•
Forward Diode Voltage	V <sub>SD</sub>	$V_{GS} = 0 \text{ V}, I_S = -1.1 \text{ A}$		-0.8	-1.2	V
Reverse Recovery Time	t <sub>RR</sub>			20	40	ns
Charge Time	ta	V <sub>GS</sub> = 0 V, dI <sub>S</sub> /dt = 100 A/μ	s.	15		
Discharge Time	tb	I <sub>S</sub> = 1.0 A	-,	5		
Reverse Recovery Charge	Q <sub>RR</sub>	1		0.01		μС

Pulse test: pulse width ≤ 300 μs, duty cycle ≤ 2%
 Switching characteristics are independent of operating junction temperatures

# TYPICAL PERFORMANCE CURVES (T<sub>J</sub> = 25°C unless otherwise noted)

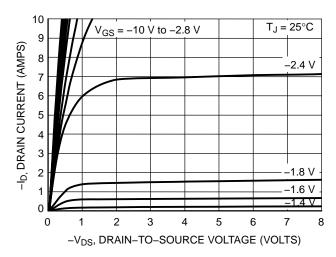
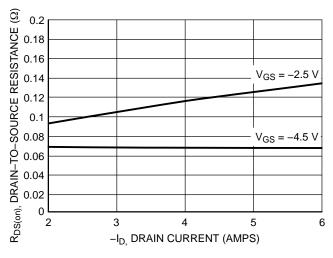


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



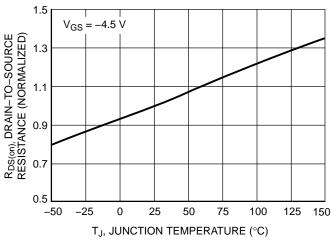


Figure 3. On–Resistance vs. Drain Current and Gate Voltage

Figure 4. On–Resistance Variation with Temperature

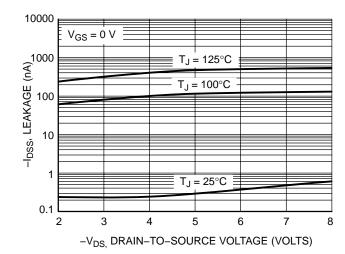
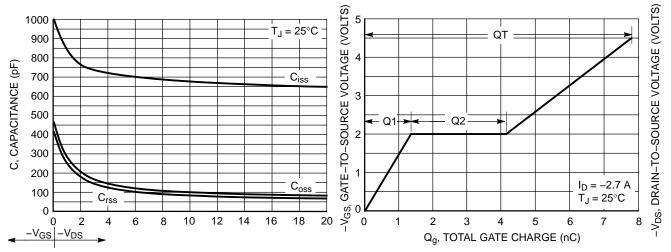


Figure 5. Drain-to-Source Leakage Current vs. Voltage

# TYPICAL PERFORMANCE CURVES (T<sub>J</sub> = 25°C unless otherwise noted)



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 6. Capacitance Variation

Figure 7. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

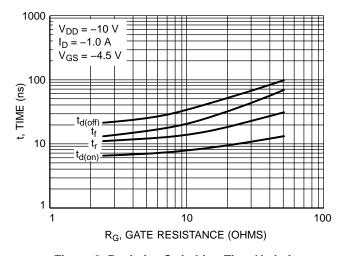


Figure 8. Resistive Switching Time Variation vs. Gate Resistance

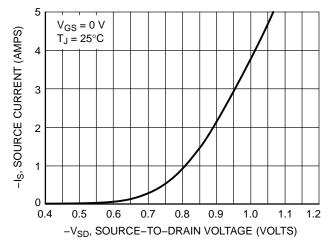


Figure 9. Diode Forward Voltage vs. Current

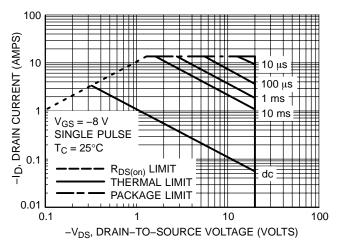
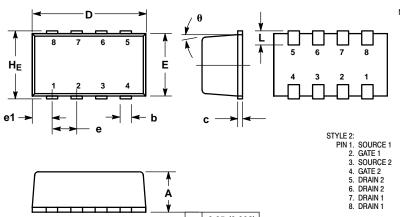


Figure 10. Maximum Rated Forward Biased Safe Operating Area

# **PACKAGE DIMENSIONS**

ChipFET™ CASE 1206A-03 ISSUE G



0.05 (0.002)

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

  2. CONTROLLING DIMENSION: MILLIMETER.

  3. MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.

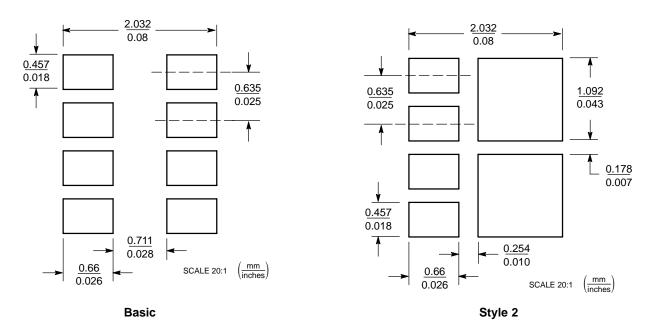
  4. LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.

  5. DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.

  6. NO MOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.

	MILLIMETERS			INCHES				
DIM	MIN	NOM	MAX	MIN	NOM	MAX		
Α	1.00	1.05	1.10	0.039	0.041	0.043		
b	0.25	0.30	0.35	0.010	0.012	0.014		
С	0.10	0.15	0.20	0.004	0.006	0.008		
D	2.95	3.05	3.10	0.116	0.120	0.122		
E	1.55	1.65	1.70	0.061	0.065	0.067		
е	0.65 BSC				0.025 BSC			
e1	0.55 BSC				0.022 BSC			
L	0.28	0.35	0.42	0.011	0.014	0.017		
HE	1.80	1.90	2.00	0.071	0.075	0.079		
θ	5° NOM				5° NOM			

## **SOLDERING FOOTPRINT\***



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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